

IDS 04/27/2006

INFORMATION DISCLOSURE CITATION <i>(Use several sheets if necessary)</i>				Docket Number (Optional) DE920020016US1	Application Number 10/620057	RECEIVED CENTRAL FAX CENTER	
Applicant(s) Appinger et al				Filing Date 7/30/2003	Coop Art Unit 2138	APR 27 2006	
U.S. PATENT DOCUMENTS							
EXAMINER INITIAL	REF	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
U.S. PATENT APPLICATION PUBLICATIONS							
EXAMINER INITIAL	REF	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
FOREIGN PATENT DOCUMENTS							
REF	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	Trademarks	
						YES	NO
OTHER DOCUMENTS <i>(Including Author, Title, Date, Pertinent Pages, Etc.)</i>							
PC		"LFSR-Coded Test Patterns for Scan Designs" by B. Kouemmann, Pages 237-242					
PC		"Decompression of Test Data Using Variable-Length Seed LFSRs" by J. Rajski et al, 1995 IEEE, Pages 426-433					
EXAMINER <i>/Phung Chung/</i>			DATE CONSIDERED 06/09/2006				
EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP Section 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.							